

P-channel enhancement mode vertical DMOS FET

ZETEX SEMICONDUCTORS
ZVP0535

FEATURES

- Compact geometry
- Fast switching speeds
- No secondary breakdown
- Excellent temperature stability
- High input impedance
- Low current drive
- Ease of paralleling

DESCRIPTION

A compact interdigitated geometry forms the basis of this Zetex MOSFET. Optimised for low on-resistance, low capacitance and fast switching, this device is manufactured using the latest computer controlled processing techniques in order to achieve greater stability, reliability and ruggedness.



E LINE (TO 92)
SUFFIX A



TO-39
SUFFIX B

PRODUCT SUMMARY

Part No.	BV_{DSS}	I_D	$R_{DS(on)}$
ZVP0535A	-350V	-0.05A	100 Ω
ZVP0535B	-350V	-0.12A	100 Ω

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ABSOLUTE MAXIMUM RATINGS

Parameters		E-line	TO-39	Unit
V_{DS}	Drain-source voltage	-350	-350	V
I_D	Continuous drain current (@ $T_A = 25^\circ\text{C}$)	-0.05	-0.05	A
I_D	Continuous drain current (@ $T_C = 25^\circ\text{C}$)	—	-0.12	A
I_{DM}	Pulsed drain current	-0.48	-0.48	A
V_{GS}	Gate-source voltage	± 20	± 20	V
P_D	Max. power dissipation (@ $T_A = 25^\circ\text{C}$)	0.7	0.7	W
P_D	Max. power dissipation (@ $T_C = 25^\circ\text{C}$)	—	5	W
T_J, T_{stg}	Operating/storage temperature range	-55 to +150		$^\circ\text{C}$

ELECTRICAL CHARACTERISTICS (at $T = 25^\circ\text{C}$ unless otherwise stated)

Parameter		Min.	Max.	Unit	Conditions
BV_{DSS}	Drain-source breakdown voltage	-350	—	V	$I_D = -1\text{mA}, V_{GS} = 0\text{V}$
$V_{GS(th)}$	Gate-source threshold voltage	-1.5	-4.5	V	$I_D = -1\text{mA}, V_{DS} = V_{GS}$
I_{GSS}	Gate-body leakage	—	100	nA	$V_{GS} = \pm 20\text{V}, V_{DS} = 0\text{V}$
I_{DSS}	Zero gate voltage drain current	—	-20	μA	$V_{DS} = \text{Max. rating}, V_{GS} = 0\text{V}$
		—	-2	mA	$V_{DS} = 0.8 \times \text{Max. rating}$ $V_{GS} = 0\text{V}$ ($T = 125^\circ\text{C}$) (2)
$I_{D(on)}$	On-state drain current (1)	-120	—	mA	$V_{DS} = -25\text{V}, V_{GS} = -10\text{V}$
$R_{DS(on)}$	Static drain-source on-state resistance (1)	—	100	Ω	$I_D = -50\text{mA}, V_{GS} = -10\text{V}$
g_{fs}	Forward transconductance (1) (2)	40	—	mS	$V_{DS} = -25\text{V}, I_D = -50\text{mA}$
C_{iss}	Input capacitance (2)	—	120	pF	$V_{DS} = -25\text{V}, V_{GS} = 0\text{V}$ $f = 1\text{MHz}$
C_{oss}	Common source output capacitance (2)	—	20	pF	
C_{rss}	Reverse transfer capacitance (2)	—	5	pF	
$t_{d(on)}$	Turn-on delay time (2) (3)	—	10	ns	$V_{DD} \approx -25\text{V}, I_D = -50\text{mA}$
t_r	Rise time (2) (3)	—	15	ns	
$t_{d(off)}$	Turn-off delay time (2) (3)	—	15	ns	
t_f	Fall time (2) (3)	—	20	ns	

(1) Measured under pulsed conditions. Width = $300\mu\text{s}$. Duty cycle $\leq 2\%$.

(2) Sample test.

(3) Switching times measured with 50Ω source impedance and $< 5\text{ns}$ rise time on a pulse generator.

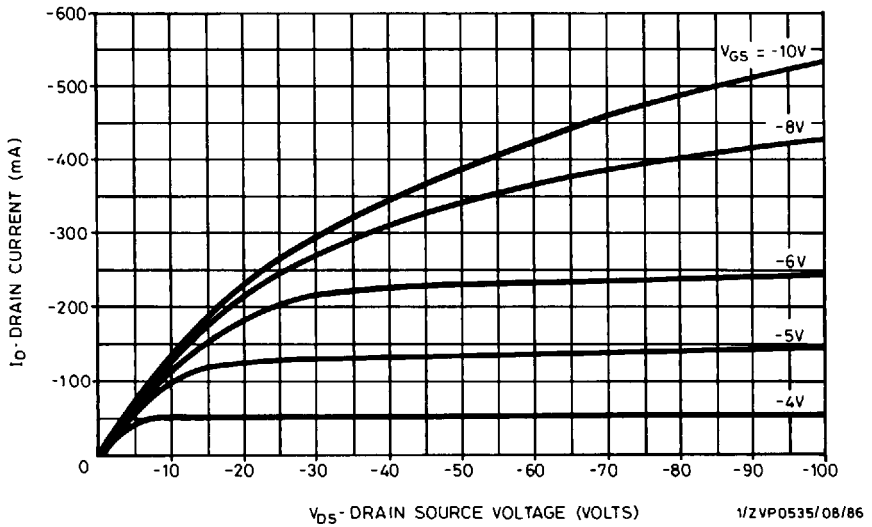


Fig. 1 Typical output characteristics

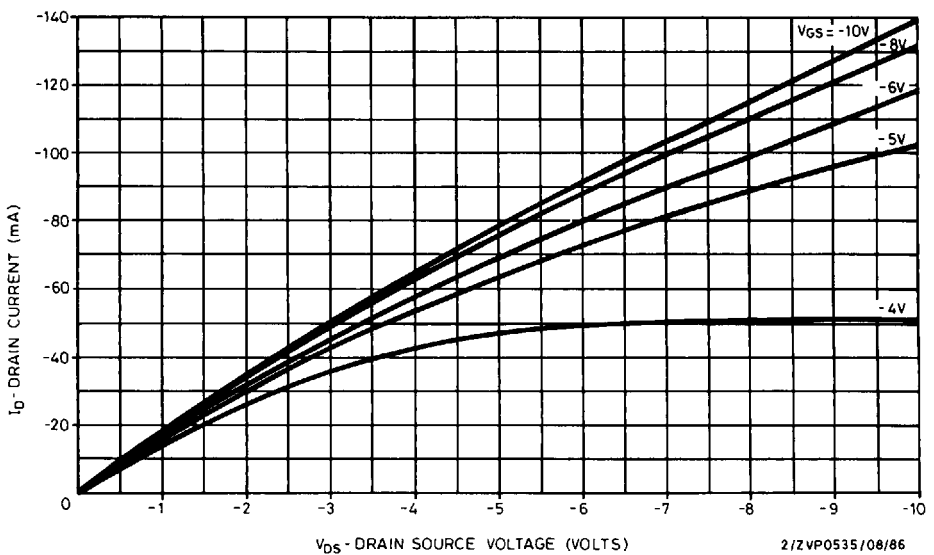


Fig. 2 Typical saturation characteristics

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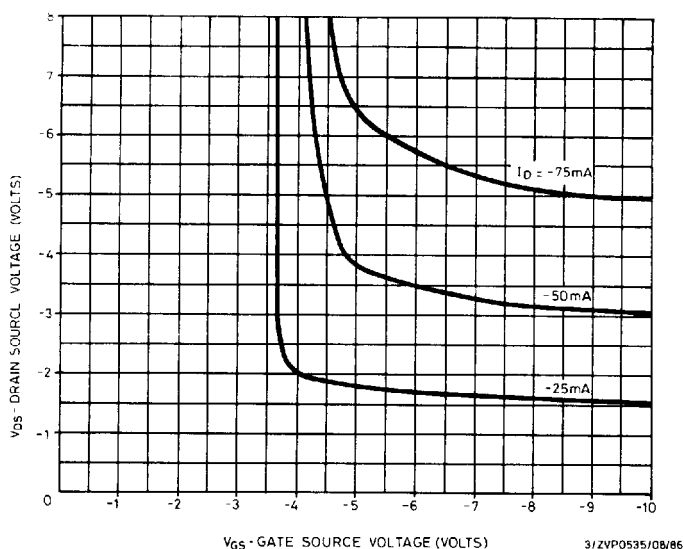


Fig. 3 Typical voltage saturation characteristics

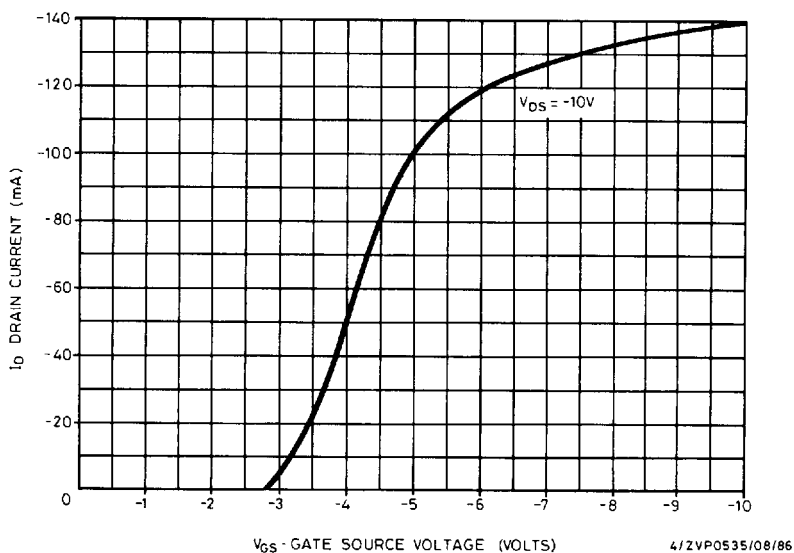


Fig. 4 Typical transfer characteristics

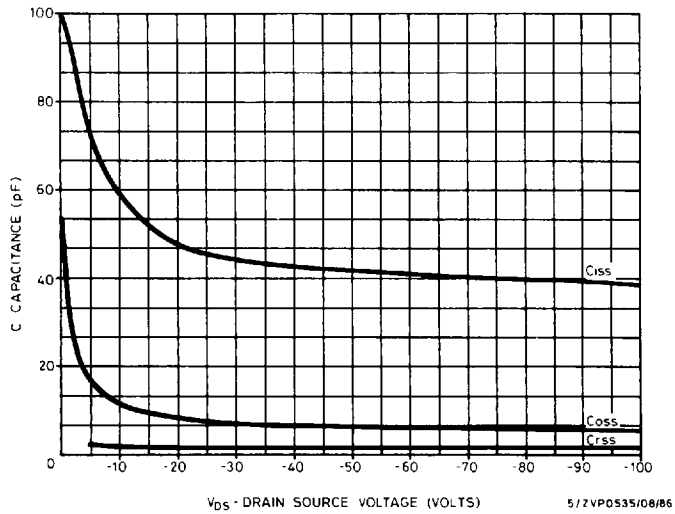


Fig. 5 Typical capacitance v drain-source voltage

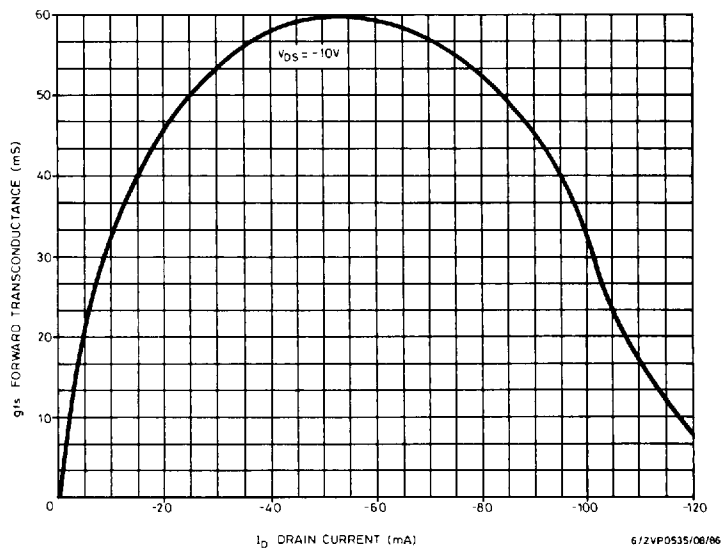
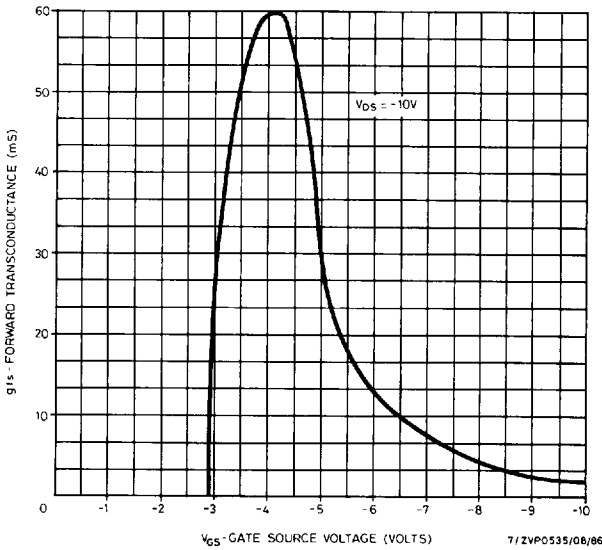
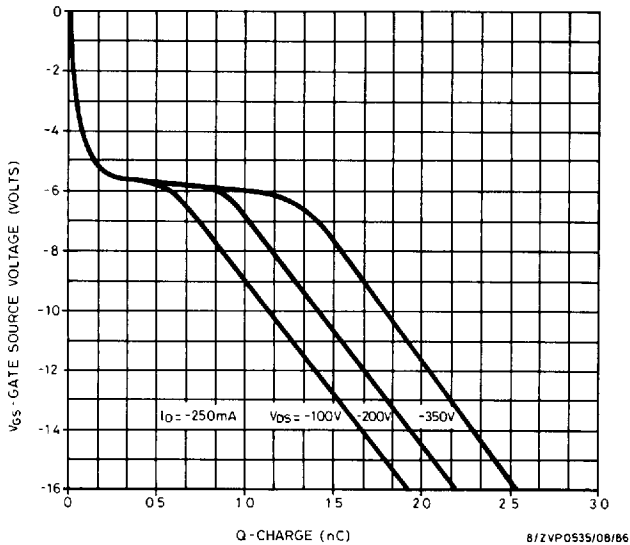


Fig. 6 Typical transconductance v drain current

ZVP0535**ZETEX SEMICONDUCTORS****Fig. 7 Typical transconductance v gate-source voltage****Fig. 8 Typical gate charge v gate-source voltage**

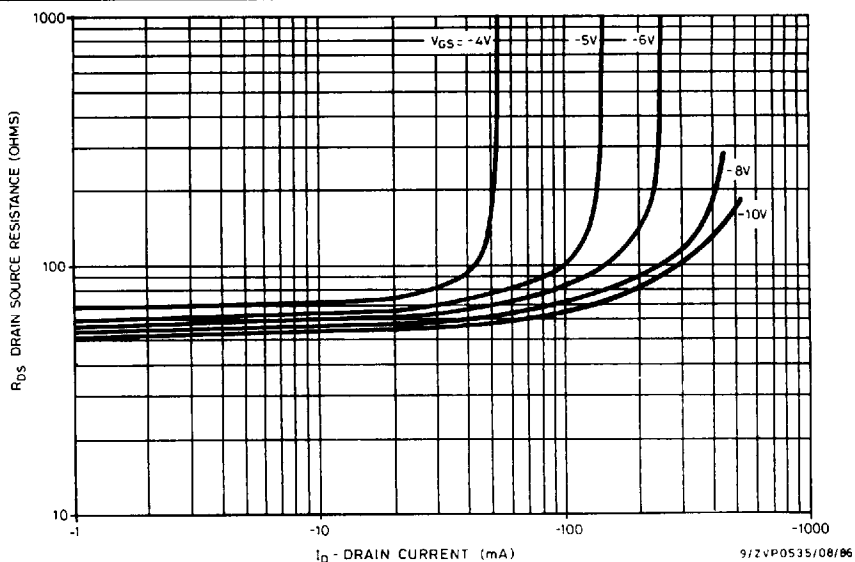


Fig. 9 Typical on-resistance v drain current

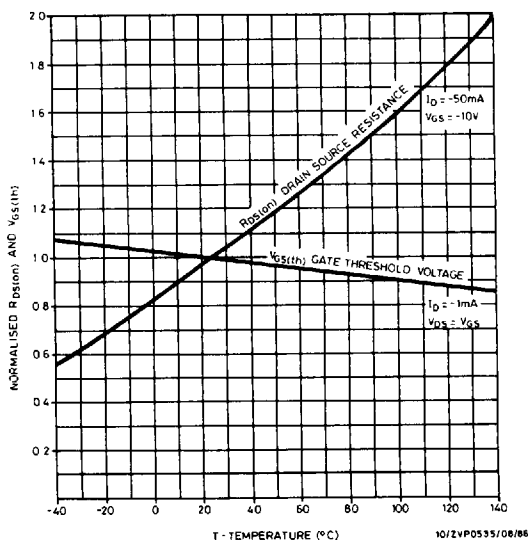


Fig. 10 Normalised $R_{DS(on)}$ and $V_{GS(th)}$ v temperature

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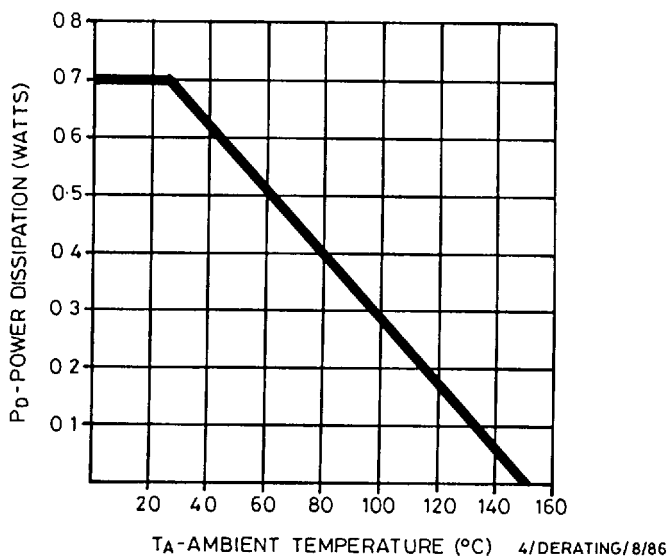


Fig. 11 Power v temperature derating curve (ambient)

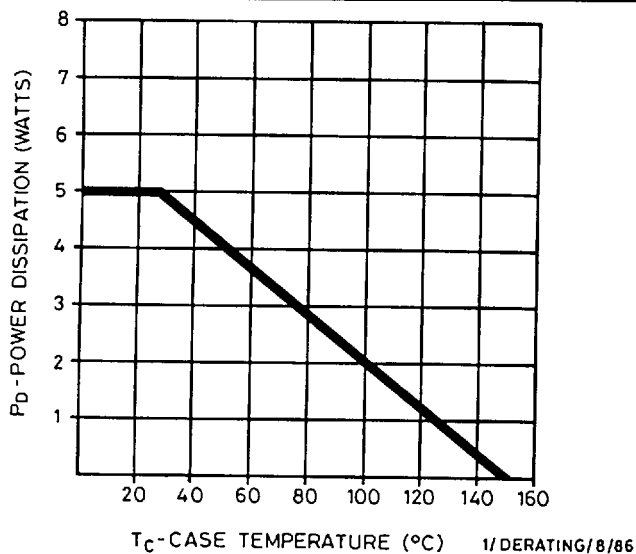


Fig. 12 Power v temperature derating curve (case)